

Notice of References Cited

Application/Control No.

10/617,817

Applicant(s)/Patent Under
Reexamination
TERAISHI, TOSHIO

Examiner

Roberto Velez

Art Unit

2829

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0109552	08-2002	Tran et al.	331/36.00C
*	B	US-6,476,789	11-2002	Sakaguchi et al.	345/100
*	C	US-6,219,808	04-2001	Sengoku, Shoichiro	714/724
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.